

Notice of References Cited	Application/Control No. 10/705,591	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Jason M. Han	Art Unit 2875	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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	N	WO 03/032073 A1	04-2003	Japan	Onishi et al.	G02F 1/1335
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NON-PATENT DOCUMENTS

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